## Search Notes



10666241 Examiner	OGAWA ET AL.  Art Unit
••	Reexamination
Application/Control No.	Applicant(s)/Patent Under

2624

SEARCHED					
Class	Subclass	Date	Examiner		
382	141,144,145,147	02/28/07	JP		
356	500,498,496,450	02/28/07	JP		

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SEARCH NOTES		
Search Notes	Date	Examiner
See attached East Search Report	02/28/07	JP
See updated East (US -pat, PG-pub) IEEE and Inventor search.	11/25/2008	JP
See the updated East, IEEE and the Inventor Search	05/29/2009	JP

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	

/J. A. P./ Examiner.Art Unit 2624	

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